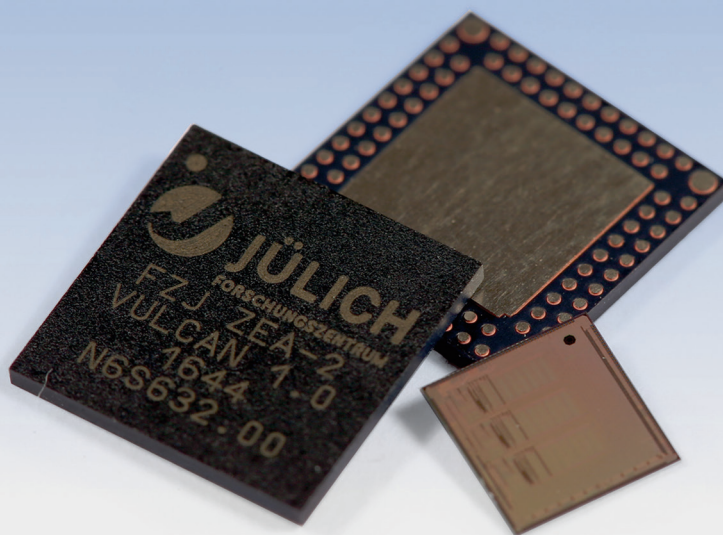


Digital Signal Processing and Mixed Signal Control of Receiver Circuitry for Large-Scale Particle Detectors

Pavithra Muralidharan

Information

Band / Volume 61

ISBN 978-3-95806-489-8

Forschungszentrum Jülich GmbH
Zentralinstitut für Engineering, Elektronik und Analytik (ZEA)
Systeme der Elektronik (ZEA-2)

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Schriften des Forschungszentrums Jülich
Reihe Information / Information

Band / Volume 61

ISSN 1866-1777

ISBN 978-3-95806-489-8

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